

• General Description

The AGMH03N10H combines advanced trench MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$.

This device is ideal for load switch and battery protection applications.

Features

- Advance high cell density Trench technology
- Low R_{DS(ON)} to minimize conductive loss
- Low Gate Charge for fast switching
- Low Thermal resistance
- 100% Avalanche tested
- 100% DVDS tested

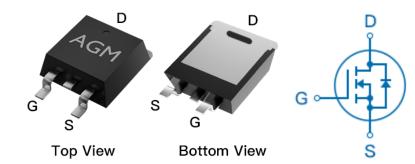
Application

- MB/VGA Vcore
- SMPS 2nd Synchronous Rectifier
- POL application
- BLDC Motor driver

Product Summary

BVDSS	RDSON	ID	
100V	2.8mΩ	160A	

TO-263Pin Configuration



Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
AGMH03N10H	AGMH03N10H	TO-263	330mm	25mm	800

Table 1. Absolute Maximum Ratings (TA=25℃)

Symbol	pol Parameter		Unit
VDS	Drain-Source Voltage (VGS=0V)	100	V
VGS	Gate-Source Voltage (VDS=0V)	±20	V
ID	Drain Current-Continuous(Tc=25℃) (Note 1)	160	А
	Drain Current-Continuous(Tc=100℃)	107	А
IDM (pluse)	Drain Current-Pulsed (Note 2)	640	А
PD	Maximum Power Dissipation(Tc=25℃)	227	W
	Maximum Power Dissipation(Tc=100℃)	91	w
EAS	EAS Avalanche energy (Note 3)		mJ
TJ,TSTG Operating Junction and Storage Temperature Range		-55 To 150	$^{\circ}$

Table 2. Thermal Characteristic

Symbol	Parameter	Тур	Max	Unit
RθJA	Thermal Resistance Junction-ambient (Steady State) ¹		60	°C/W
RøJC	Thermal Resistance Junction-Case ¹		0.55	°C/W



Table 3. Electrical Characteristics (Tj=25 ℃ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Тур	Max	Unit	
On/Off States							
BVDSS	Drain-Source Breakdown Voltage	VGS=0V ID=250µA	100			V	
IDSS	Zero Gate Voltage Drain Current	VDS=100V,VGS=0V			1	μA	
IGSS	Gate-Body Leakage Current	VGS=±20V,VDS=0V			±100	nA	
VGS(th)	Gate Threshold Voltage	VDS=VGS,ID=250μA	2.0	3.0	4.0	V	
gFS	Forward Transconductance	VDS=5V,ID=20A		45		S	
RDS(on)	Drain-Source On-State Resistance	VGS=10V, ID=50A		2.8	4.2	mΩ	
Dynamic (Characteristics						
Ciss	Input Capacitance	VDS=40V,VGS=0V,		7698		pF	
Coss	Output Capacitance	F=1MHZ		821		pF	
Crss	Reverse Transfer Capacitance			115		pF	
Rg	Gate resistance	VGS=0V, VDS=0V,f=1.0MHz		1.5		Ω	
Switching	Times						
td(on)	Turn-on Delay Time			32		nS	
tr	Turn-on Rise Time	VGS=10V,VDS=50V		45		nS	
td(off)	Turn-Off Delay Time	RGEN=3Ω		52		nS	
tf	Turn-Off Fall Time			31		nS	
Qg	Total Gate Charge			95		nC	
Qgs	Gate-Source Charge	VGS=10V, VDS=50V, ID=50A		25		nC	
Qgd	Gate-Drain Charge			21		nC	
Source-Drain Diode Characteristics							
ISD	Source-Drain Current(Body Diode)				160	Α	
VSD	Forward on Voltage	VGS=0V,IS=50A			1.2	V	
trr	Reverse Recovery Time	IS=50A , dI/dt=100A/μs ,		85		ns	
Qrr	Reverse Recovery Charge	TJ=25℃		254		nc	

Notes 1. The maximum current rating is package limited.

Notes 2.Repetitive Rating: Pulse width limited by maximum junction temperature

Notes 3.EAS condition: TJ=25 $^{\circ}$ C,VDD=50V,Vgs=10V, ID=57A,L=0.5mH,RG=25ohm



Typical Performance Characteristics

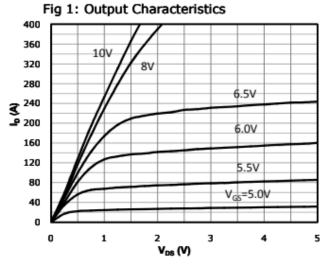


Fig 2: Transfer Characteristics

V_{DS}=5V

V_{DS}=5V

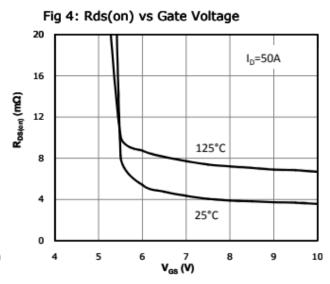
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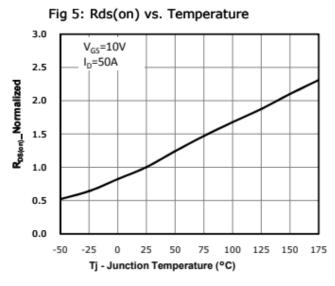
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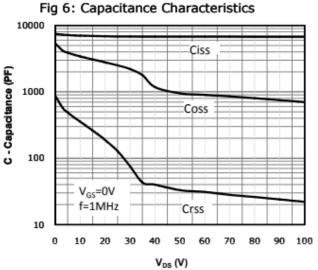
125°C

25°C

Fig 3: Rds(on) vs Drain Current and Gate Voltage 7.0 6.0 5.0 V_{GS}=10V 4.0 3.0 2.0 1.0 10 20 30 40 50 60 70 80 90 100 I_D (A)







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2

0

0 10 20 30

Fig 7: Gate Charge Characteristics 10 $V_{DS}=50V$ I_D=20A 8 4

50

Qg (nC)

40

60

70

80 90 100

Fig 8: Body-diode Forward Characteristics 100 I_s - Diode Current(A) 10 125°C 25°C 1 0.1 0.01 0.2 0.4 0.6 0.8 1 1.2 V_{SD} - Diode Forward Voltage(V)

Fig 9: Power Dissipation 250

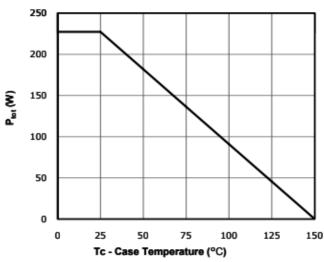


Fig 10: Drain Current Derating

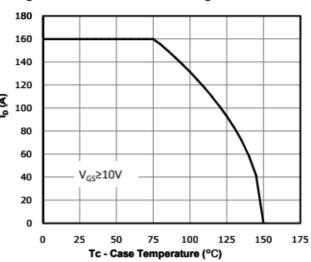
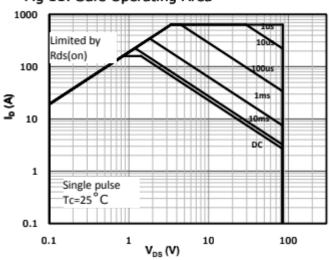


Fig 11: Safe Operating Area





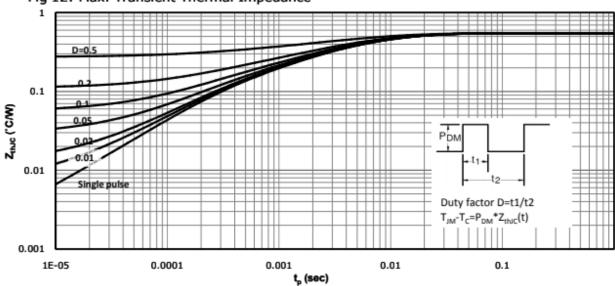
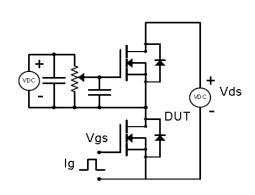


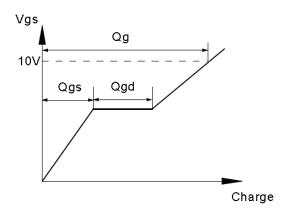
Fig 12: Max. Transient Thermal Impedance



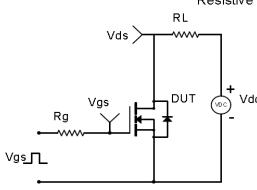
Test Circuit & Waveform

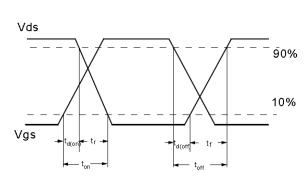
Gate Charge Test Circuit & Waveform



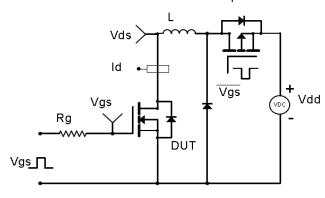


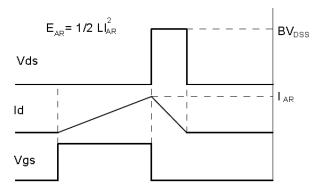
Resistive Switching Test Circuit & Waveforms



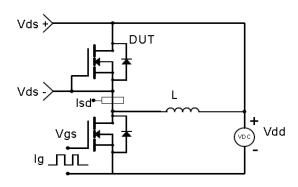


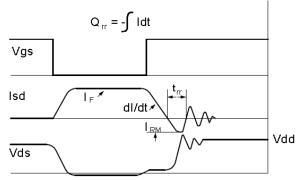
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





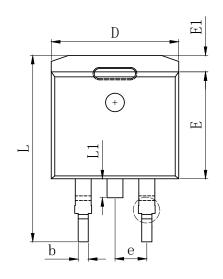
Diode Recovery Test Circuit & Waveforms

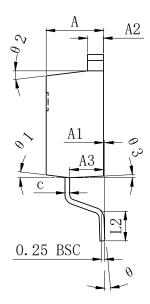


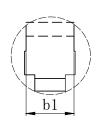




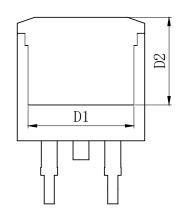
TO-263 PACKAGE INFORMATION

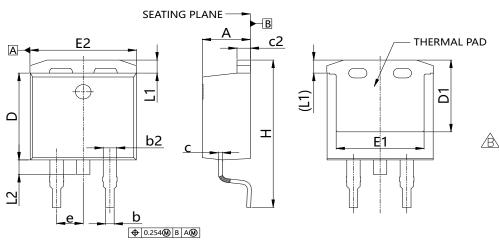


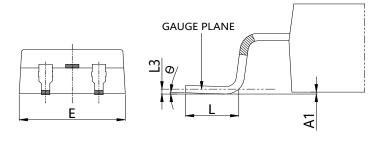




SYMBOL -	MILLIMETER				
SIMBUL	MIN	Тур.	MAX		
A	4. 370	4. 570	4.770		
A1	0.000		0.250		
A2	1.220	1. 270	1.420		
A3	2. 490	2. 690	2.890		
b	0.700	0.810	0.960		
b1	1.170	1. 270	1.470		
С	0.300	0.380	0.530		
D	9.860	10. 160	10. 360		
D1	8.400 REF				
D2	7.073 REF				
Е	8.500	8. 700	8.900		
E1	1.070	1. 270	1.470		
е		2.540 TYP			
L	14.700	15. 100	15. 500		
L1	1.400	1.550	1.700		
L2	2.000	2.300	2.600		
θ	0°		9°		
θ 1	7° TYP				
θ2	7° TYP				
θ3	3° TYP				







	S Y					
	SY M B O L	MILLIMETER				
	Ľ	MIN.	NOMINAL	MAX.		
	Α	4.47	4.57	4.67		
	A1	0.00	0.10	0.25		
	b	0.71	0.81	0.91		
	b2	1.17	1.27	1.37		
	С	0.360	0.381	0.500		
\	c2	1.17	1.27	1.37		
	D	8.70	9.00	9.30		
	D1	7.10	7.44	7.80		
	Е	9.90	10.11	10.30		
	E1	8.08	8.38	8.68		
	E2	10.00	10.16	10.30		
	е	2.44	2.54	2.64		
	Н	15.00	15.28	15.60		
	L	2.25	2.54	2.80		
	L1	1.10	1.35	1.60		
	L2			1.78		
	L3		0.254 BSC			
	θ	0°		8°		



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